May 1998 FAIRCHILD SEMICONDUCTOR TM NDS9955 **Dual N-Channel Enhancement Mode Field Effect Transistor General Description** Features SO-8 N-Channel enhancement mode power field effect = 3.0 A, 50 V. $\mathrm{R}_{\mathrm{DS(ON)}}$ = 0.130 Ω @ V_{GS} = 10 V, transistors are produced using Fairchild's proprietary, high $\mathrm{R}_{\mathrm{DS(ON)}}$ = 0.200 Ω @ V_{GS} = 4.5 V. cell density, DMOS technology. This very high density High density cell design for extremely low R_{DS(ON)}. process is especially tailored to provide superior switching performance and minimize on-state resistance. These High power and current handling capability in a widely devices are particularly suited for low voltage applications used surface mount package. such as disk drive motor control, battery powered circuits where fast switching, low in-line power loss, and resistance Dual MOSFET in surface mount package. to transients are needed. SOT-23 SuperSOT[™]-6 SuperSOT[™]-8 SOIC-16 SO-8 SOT-223 **D2** 5 4 D2 **D1** 6 3 **D1** 7 2 G2 S2 G1 8 1 **SO-8** pin[']1 **S1**

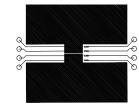
Absolute Maximum Ratings $T_A = 25^{\circ}C$ unless other wise noted

Symbol	Parameter	NDS9955	Units
V _{DSS}	Drain-Source Voltage	50	V
V _{GSS}	Gate-Source Voltage	±20	V
I _D	Drain Current - Continuous (Note 1a)	3	А
	- Pulsed	10	
P _D	Power Dissipation for Dual Operation	2	W
	Power Dissipation for Single Operation (Note 1a)	1.6	
	(Note 1b)	1	
	(Note 1c)	0.9	
T_,T _{stg}	Operating and Storage Temperature Range	-55 to 150	°C
THERMA	L CHARACTERISTICS		
R _{eja}	Thermal Resistance, Junction-to-Ambient (Note 1a)	78	°C/W
R _{eJC}	Thermal Resistance, Junction-to-Case (Note 1)	40	°C/W

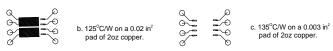
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Symbol	Parameter	Conditions		Min	Тур	Max	Units
OFF CHAR	ACTERISTICS						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \text{ I}_{D} = 250 \mu\text{A}$		50			V
$\Delta BV_{DSS} / \Delta T_{J}$	Breakdown Voltage Temp. Coefficient	$I_p = 250 \mu$ A, Referenced to 25 °C			60		mV/ °C
DSS	Zero Gate Voltage Drain Current	$V_{\rm DS} = 40 \text{ V}, \ V_{\rm GS} = 0 \text{ V}$				2	μA
GSSF	Gate - Body Leakage, Forward	$V_{GS} = 20 \text{ V}, \text{ V}_{DS} = 0 \text{ V}$				100	nA
GSSR	Gate - Body Leakage, Reverse	$V_{gs} = -20 \text{ V}, \text{ V}_{ps} = 0 \text{ V}$				-100	nA
ON CHARA	CTERISTICS (Note 2)						
V _{GS(th)}	Gate Threshold Voltage $V_{DS} = V_{GS}, I_D = 250 \mu A$			1	1.7	3	V
			T _J =125°C	0.7		2.2	
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 3 \text{ A}$			0.076	0.13	Ω
			T _J =125°C		0.124	0.2	
		$V_{GS} = 4.5 \text{ V}, \ \text{I}_{D} = 1.5 \text{ A}$			0.103	0.2	
			T _J =125°C		0.166	0.3	
D(ON)	On-State Drain Current	$V_{GS} = 10 \text{ V}, V_{DS} = 10 \text{ V}$		10			А
FS	Forward Transconductance	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 3 \text{ A}$			5.3		S
DYNAMIC (CH ARACTERISTICS						
C _{iss}	Input Capacitance	$V_{DS} = 25 \text{ V}, \text{ V}_{GS} = 0 \text{ V},$ f = 1.0 MHz			345		pF
C _{oss}	Output Capacitance				110		pF
C _{rss}	Reverse Transfer Capacitance				25		pF
WITCHING	CHARACTERISTICS (Note 2)						
D(on)	Turn - On Delay Time	$V_{DS} = 25 \text{ V}, \text{ I}_{D} = 1 \text{ A}$ V _{GS} = 10 V, R _{GEN} = 6 Ω			5	20	ns
	Turn - On Rise Time				7.5	20	
D(off)	Turn - Off Delay Time				20	70	
f	Turn - Off Fall Time				7	5	
ک ⁶	Total Gate Charge	$V_{DS} = 25 \text{ V}, \text{ I}_{D} = 2 \text{ A},$ $V_{GS} = 10 \text{ V}$			12.9	30	nC
$\hat{\boldsymbol{\lambda}}_{gs}$	Gate-Source Charge				1.7		
2 _{gd}	Gate-Drain Charge				3.2		
DRAIN-SOU	RCE DIODE CHARACTERISTICS AND MA	XIMUM RATINGS					
s	Maximum Continuous Drain-Source Diode F	Forward Current				1.3	А
/ _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 V, I_{S} = 1.3 A$ (Note 2)			0.8	1.2	V
rr	Reverse Recovery Time	$\frac{V_{GS} = 0 \text{ V}, \text{ I}_{F} = 1.3 \text{ A},}{\text{dI}_{F}/\text{dt} = 100 \text{ A}/\mu\text{s}}$			40		ns
rr	Reverse Recovery Current				1.5		А

design while $R_{\theta CA}$ is determined by the user's board design.

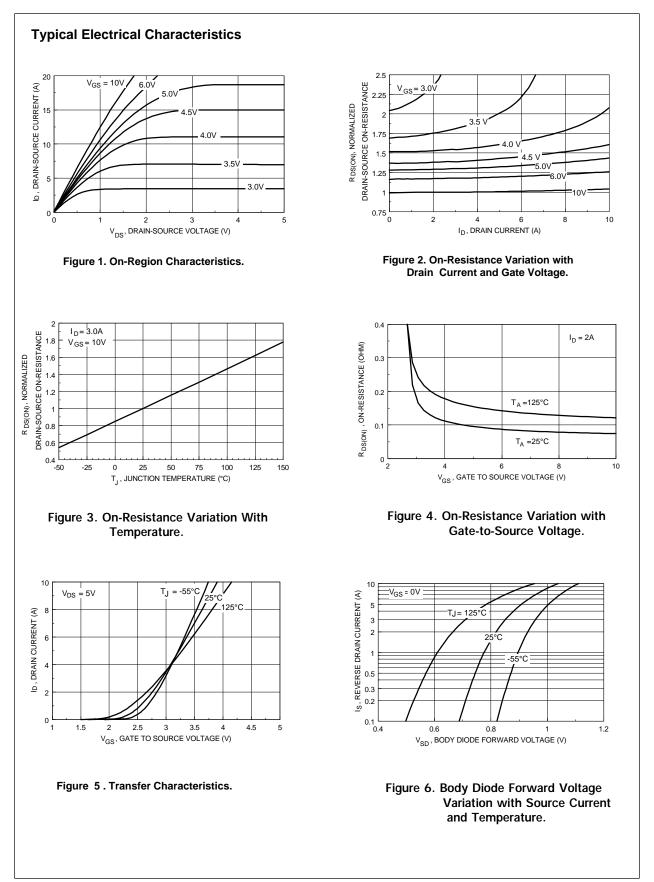


a. 78°C/W on a 0.5 in² pad of 2oz copper.

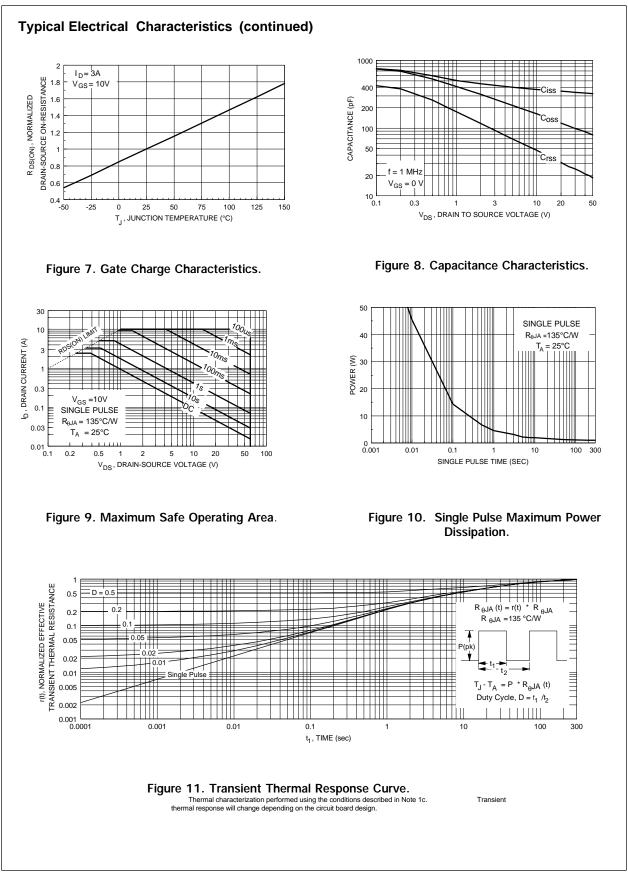


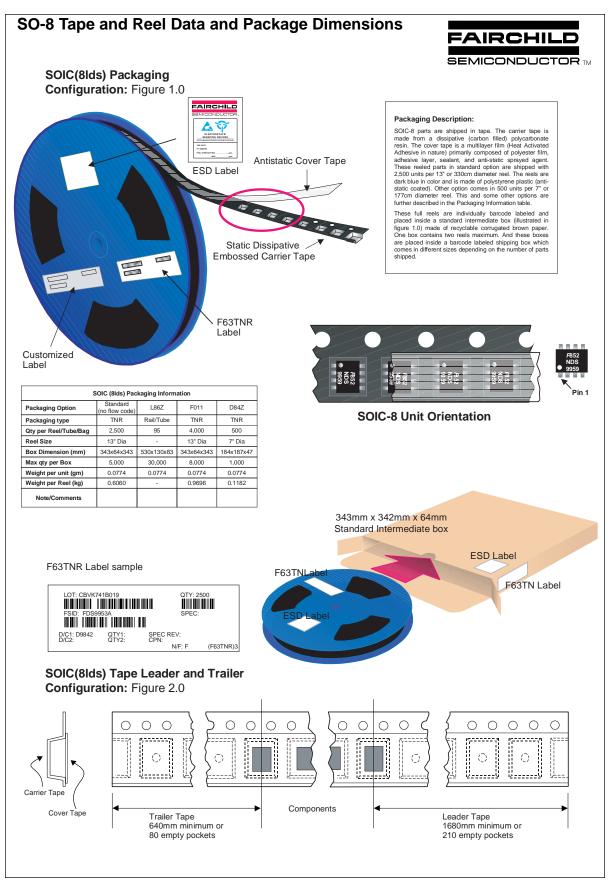
Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width \leq 300µs, Duty Cycle \leq 2.0%.

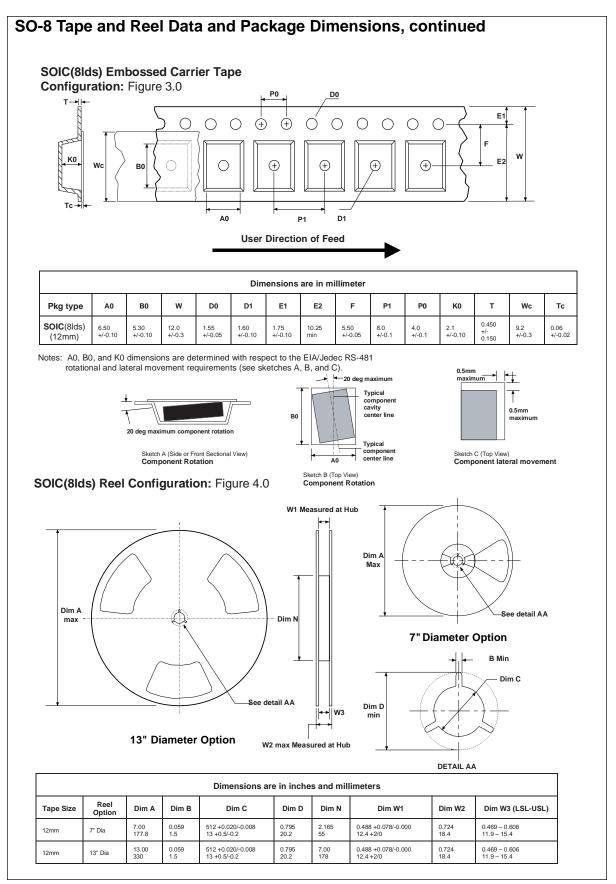


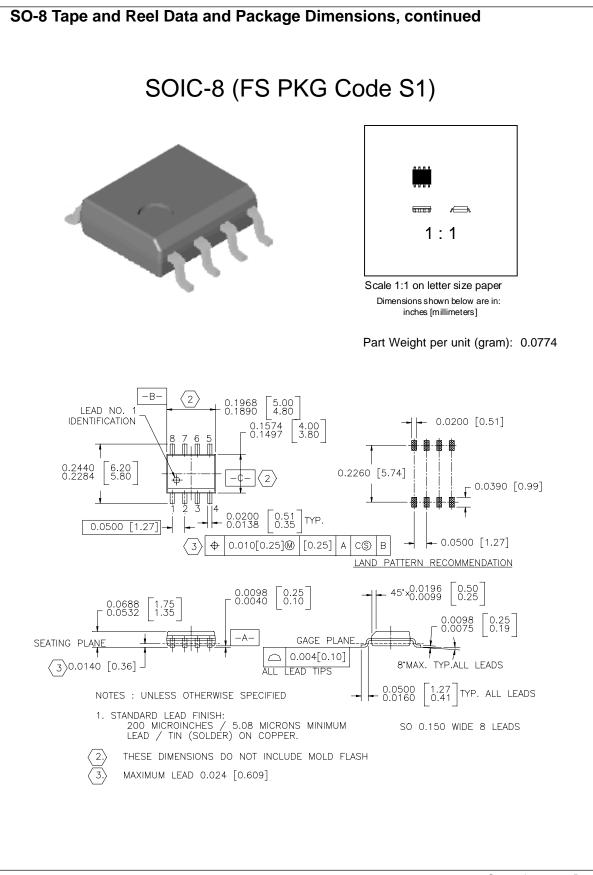
NDS9955 Rev.A





July 1999, Rev. B





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